# Curriculum Vitae Dr. Naveen Thakur

Assistant Professor-Physics (Ph.D.)

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## **PERSONAL INFORMATION**

Date of birth & Place: May 25, 1994, Solan, Himachal Pradesh (INDIA) Nationality: Indian Languages: Hindi, English Sex: Male Disabilities: None

## **EDUCATION**

Ph.D. in Science 2017-2022, (Condensed matter physics), National Institute of Technology Hamirpur (NIT-H) with Dr. Subhash Chand, Associate Professor, Department of Physics.

Thesis title: *"Fabrication, characterization and analysis of metal-insulator-semiconductor heterostructures"* 

- Fabrication and electrical characterization of solution-processed Ni/MgO/*p*-Si/Al MIS heterostructures.
- Analysis of rectifying nature of fabricated heterostructures using electric measurements and impedance spectroscopy.
- Role of interface states in affecting properties of heterostructures.

Master of Science in Physics 2014-2016, CGPA – 8.64.

Bachelor of Science – 2011-2014, Percentage – 67.3.

# AWARDS AND SCHOLARSHIPS HELD

Senior Research Fellow (SRF) from 1<sup>st</sup> August' 2019 to August' 2022. Junior Research Fellow (JRF) 1<sup>st</sup> August' 2017 to August' 2019. GATE 2017, Percentile: 97.71, Rank (GATE-2019 all India): 427 NET/HP-SET-2018 (Himachal Pradesh State eligibility test)-Physics.

#### **RESEARCH INTEREST**

Physics of semiconductor devices,

Fabrication and characterization of heterostructures, Studies of topological semimetals Interfaces.

## **INSTRUMENT SKILLS**

Keithley 2400 Source meter (Current-voltage measurements). Wayne Kerr–6520 A impedance analyser. IR Spectrophotometer (JASCO-FT-IR Model-410). Thermal vacuum coating unit model 12A4D.

## PUBLICATIONS

Published	h-index: 3	i10-index: 2	Total citation: 110
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- Naveen Kumar and Subhash Chand, "Effects of temperature, bias and frequency on the dielectric properties and electrical conductivity of Ni/SiO<sub>2</sub>/p-Si/Al MIS Schottky diode", J. Alloys Compd., vol. 817, pp. 153294, 2019.
- Naveen Kumar and Subhash Chand, "Analysis of rectifying metal-semiconductor interface using impedance spectroscopy at low temperatures," Physica B Condens. Matter., vol. 599, pp. 412547, 2020.
- 3. Naveen Kumar and Subhash Chand, "Scrutinization of non-saturation behaviour of reverse current-voltage characteristics in Ni/SiO<sub>2</sub>/p-Si/Al diode," Superlattices Microstructur., vol. 160, pp. 107088, 2021.
- 4. Naveen Kumar and Subhash Chand, "Fabrication and electrical characterization of solution-processed Ni/MgO/p-Si/Al MIS Schottky diodes", Appl. Phys. A, vol. 128, pp. 226, 2022.
- Seema, Naveen Kumar and Subhash Chand, "Effect of Mg<sup>2+</sup> ions substitution on phase formation, structural and optical Zn<sub>1-x</sub>Mg<sub>x</sub>O structure", J. Mater. Sci.: Mater. Electron, vol. 33, pp. 861, 2022.
- 6. Kalpna Thakur, **Naveen Kumar** and NovRattan Sharma, "Effects of lockdown and pandemic on mental health of children. (Scientific letter) Indian Journal of Pediatrics", vol. 87, pp. 552, 2020.
- Seema, Naveen Kumar and Subhash Chand, "Structural, morphological, optical and dielectric properties of Ti<sub>1-x</sub>FeO<sub>2</sub> nanoparticles synthesized using sol-gel method", J. Sol-Gel Sci. Tech, October 2022.

# **CONFERENCES ATTENDED AND PAPER PRESENTED**

- 1. Naveen Kumar and Subhash Chand, "On the crossing behaviour of forward current-voltage characteristics of Ni/SiO<sub>2</sub>/p-Si/Al Schottky diodes", AIP Conf. Proceed., vol. 2220, pp. 040022, 2020.
- 2. International Conference on Condensed Matter & Applied Physics, Rajasthan, India, 14<sup>th</sup> 15<sup>th</sup> October 2019.
- 3. New Generation functional materials and their applications (NFMA-2021) organized by Department of Material Science and Engineering, NIT-Hamirpur, 3<sup>rd</sup>-7<sup>th</sup> February, 2021.
- 4. **Online National Conference** on Recent Trends of Innovation in Basic & Applied Sciences (NCRTIBAS-2021), 22<sup>nd</sup> October 2021.